



Docket No.: 87391.0500

IPW
PATENT/OFFICIAL

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Kai-Ye Huang, et al.

Serial No. 10/699,830

: Group Art Unit: 2858

Filed: November 4, 2003

For: METHOD AND TEST STRUCTURES FOR MEASURING INTERCONNECT
COUPLING CAPACITANCE IN AN IC CHIP

STATUS REQUEST

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicants respectfully requests notification as to the status of the above-identified application. This application was filed on November 4, 2003. No action has been forthcoming from the U.S. Patent and Trademark Office.

Respectfully submitted,

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